

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Docket No. 25740-02A

Feng-Tso Chien

Serial No.:

To be assigned

Date Filed:

Concurrently herewith

Title:

Power Mosfet Device With Reduced Snap-Back and Being Capable of Increasing Avalanche-Breakdown Current Endurance, and Method of Manufacturing

Same

Box Patent Application U.S. Patent and Trademark Office P.O. Box 2327 Arlington, VA 22202

## PRELIMINARY AMENDMENT

Prior to issuing a first office action, please amend the application as follows:

## IN THE CLAIMS

Please add new claims 3-8 as follows:

3. (New) A power MOSFET device comprising:

an N<sup>+</sup> silicon substrate;

a gate electrode;

an  $N^-$  epitaxial layer formed above said  $N^+$  silicon substrate, at least a portion of which is intermediate the  $N^+$  silicon substrate and the gate electrode;

a P well implanted in the N epitaxial layer;

{W1200048}